


<b>Search Notes</b>  	<b>Application/Control No.</b>  10574666	<b>Applicant(s)/Patent Under Reexamination</b>  BAJAJ ET AL.
	<b>Examiner</b>  Christopher R Lea	<b>Art Unit</b>  1619

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
PLUS Search (already in IFW)	12/2/2008	/CRL/
Text Search of Patent Literature (See EAST Search History)	12/2/2008	/CRL/
Inventor Name Search (See EAST Search History and PALM)	12/2/2008	/CRL/

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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